


<b>Search Notes</b> 	<b>Application/Control No.</b> 10573297	<b>Applicant(s)/Patent Under Reexamination</b> NAKAMURA ET AL.
	<b>Examiner</b> SEAN E AEDER	<b>Art Unit</b> 1642

SEARCHED			
Class	Subclass	Date	Examiner
435	4	12/30/08	SEA

SEARCH NOTES		
Search Notes	Date	Examiner
STN (MEDLINE, BIOSIS, EMBASE, SCISEARCH, DISSABS; attached), MEDLINE, WEST (PGPB, USPT, USOC, EPAB, JPAB, DWPI; attached)	12/30/08	SEA
PALM inventor search	12/30/08	SEA
stic seq id no:48	12/30/08	SEA

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
435	4	12/30/08	SEA
	WEST (PGPB; USPT)	12/30/08	SEA
	stic seq id no:48	12/30/08	SEA

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